

OKI semiconductor

MSM5128RS

2048-WORD x 8-BIT C-MOS STATIC RAM

GENERAL DESCRIPTION

The MSM5128RS is a 2048-word by 8-bit CMOS static RAM featuring 5V power supply operation and direct TTL input/output compatibility. Since the circuitry is completely static, external clock and refreshing operations are unnecessary, making this device very easy to use. The MSM5128RS is also a CMOS silicon gate device which requires very little power during standby (maximum standby current of $50\mu A$) when there is no chip selection. Stored data is retained if the power voltage drops to 2V, thereby enabling battery back-up.

A byte system is adopted, and since there is pin compatibility with standard ultra-violet EPROMs, this device is ideal for use as a peripheral memory for microcomputers and data terminal units etc. In addition, CS and OE signals enable OR ties with the output terminals of other chips, thereby facilitating simple memory expansion and bus line control etc.

FEATURES

- Single 5V Supply
- Battery Back-up at 2V
- Operating temperature range $T_a = -40^\circ C$ to $+85^\circ C$
- Low Power Dissipation

Standby:

5128-20

1.0 μA MAX $T_a = 25^\circ C$
10 μA MAX $T_a = 60^\circ C$
50 μA MAX $T_a = 85^\circ C$

5128-12/15

0.3 μA MAX $T_a = 25^\circ C$
1.0 μA MAX $T_a = 60^\circ C$

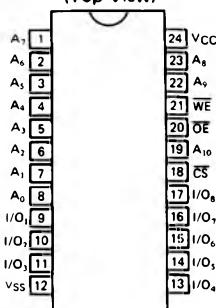
Operation:

200 mW TYP

- High Speed (Equal Access and Cycle Time)
MSM5128-12/15/20; 120 ns/150 ns/200 ns MAX
- Direct TTL Compatible. (Input and Output)
- 3-State Output
- Pin Compatible with
16K EPROM (MSM2716)
16K NMOS SRAM (MSM2128)

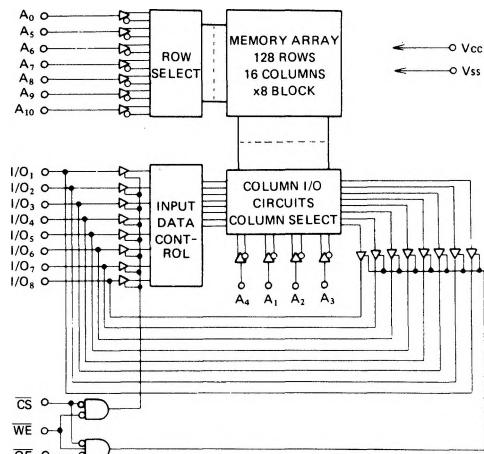


PIN CONFIGURATION (Top View)



A₀ ~ A₁₀: Address INPUTS
I/O₁ ~ I/O₈: Data Input/Output
CS: Chip Select
WE: Write Enable
OE: Output Enable
VCC, VSS: Supply Voltage

FUNCTIONAL BLOCK DIAGRAM



TRUTH TABLE

Mode	CS	WE	OE	I/O Operation
Standby	H	X	X	High Z
Read	L	H	H	High Z
	L	H	L	D _{OUT}
Write	L	L	X	D _{IN}

X : H or L

ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit	Conditions
Supply Voltage	V _{CC}	-0.3 to 7.0	V	Respect to GND
Input Voltage	V _{IN}	-0.3 to V _{CC} + 0.3	V	
Operating Temperature	T _{opr}	-40 to 85	°C	
Storage Temperature	T _{stg}	-55 to 150	°C	
Power Dissipation	P _D	1.0	W	T _a = 25°C

RECOMMENDED OPERATING CONDITION

Parameter	Symbol	Min.	Typ.	Max.	Unit	Conditions
Supply Voltage	V _{CC}	4.5	5	5.5	V	5V ± 10%
	V _{SS}		0		V	
Data Retention Voltage	V _{CCH}	2	5	5.5	V	
Input Voltage	V _{IH}	2.2		V _{CC} + 0.3	V	5V ± 10%
	V _{IL}	-0.3		0.8	V	
Output Load	C _L			100	pF	
	TTL			1		

■ STATIC RAM · MSM5128RS ■

DC CHARACTERISTICS

($V_{CC} = 5V \pm 10\%$, $T_a = -40^\circ C$ to $+85^\circ C$)

Parameter	Symbol	MSM5128-12			MSM5128-15			MSM5128-20			Unit	Test Condition	
		Min.	Typ.	Max.	Min.	Typ.	Max.	Min.	Typ.	Max.			
Input Leakage Current	I_{LI}	-1		1	-1		1	-1		1	μA	$V_{IN} = 0$ to V_{CC}	
Output Leakage Current	I_{LO}	-1		1	-1		1	-1		1	μA	$CS = V_{IH}$ or $OE = V_{IH}$ $V_{I/O} = 0$ to V_{CC}	
Output Voltage	V_{OH}	2.4			2.4			2.4			V	$I_{OH} = -1$ mA	
	V_{OL}			0.4			0.4			0.4	V	$I_{OL} = 4$ mA (5128-12) $I_{OL} = 2.1$ mA (5128-15/20)	
Standby Supply Current	I_{CCS}	T_a									μA	$CS \geq V_{CC} - 0.2V$ $V_{IN} = 0$ to V_{CC}	
		25°C			0.2			0.2		0.1			
		60°C			1.0			1.0		10			
	I_{CCS1}									50		$CS = V_{IH}$ t_{cyc} = Min. cycle	
Operating Supply Current	I_{CCA}		40	60		37	55		35	50	mA	$Min.$ $cycle$	$T_a = 0 \sim 85^\circ C$
			40	72		37	66		35	60	mA		$T_a = -40 \sim 85^\circ C$

AC CHARACTERISTICS

Test Condition

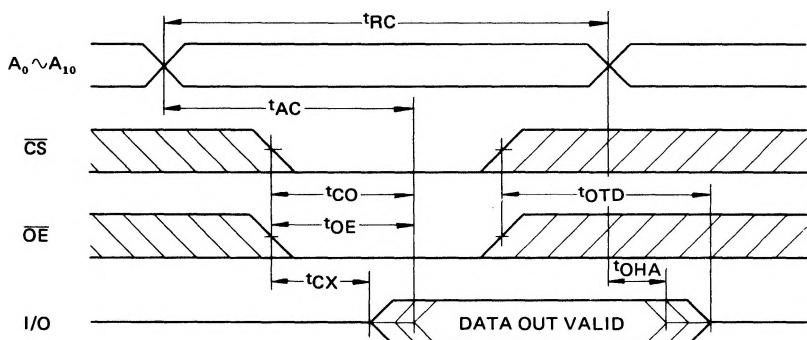
Parameter	Conditions	
	Input Pulse Level	Input Rise and Fall Times
	$V_{IH}=2.2V$, $V_{IL}=0.8V$	
Input and Output Timing Reference Level		10 ns
Output Load		1.5V
		$C_L=100$ pF, 1 TTL Gate

READ CYCLE

($V_{CC} = 5V \pm 10\%$, $T_a = -40^\circ C$ to $+85^\circ C$)

Parameter	Symbol	MSM5128-12		MSM5128-15		MSM5128-20		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
Read Cycle Time	t_{RC}	120		150		200		ns
Address Access Time	t_{AC}		120		150		200	ns
Chip Select Access Time	t_{CO}		120		150		200	ns
Output Enable to Output Valid	t_{OE}		80		100		120	ns
Chip Selection to Output Active	t_{CX}	10		15		20		ns
Output Hold Time From Address Change	t_{OHA}	10		15		20		ns
Output 3-state from Deselection	t_{OTD}	0	50	0	50	0	60	ns

READ CYCLE



- Notes:**
1. A Read occurs during the overlap of a low CS, a low OE and a high WE.
 2. t_{CX} is specified from CS or OE, whichever occurs last.
 3. t_{OTD} is specified from CS or OE, whichever occurs first.
 4. t_{OHA} and t_{OTD} are specified by the time when DATA OUT is floating.

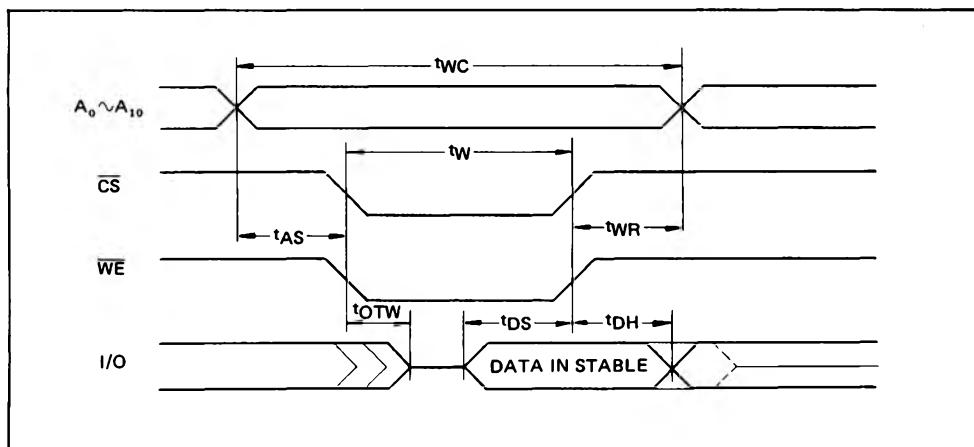
WRITE CYCLE

(V_{cc} = 5V ± 10%, T_a = -40° C to +85° C)

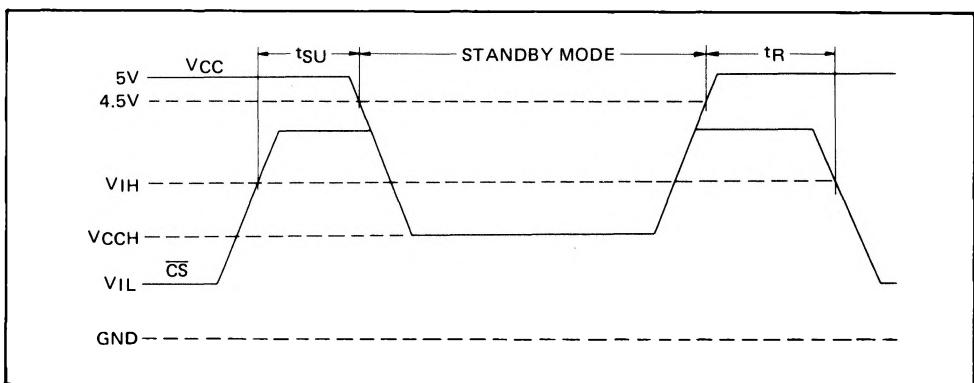
Parameter	Symbol	MSM5128-12		MSM5128-15		MSM5128-20		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
Write Cycle Time	t _{WC}	120		150		200		ns
Address to Write Setup Time	t _{AS}	15		20		20		ns
Write Time	t _W	70		90		120		ns
Write Recovery Time	t _{WR}	15		20		20		ns
Data Setup Time	t _{DS}	50		60		80		ns
Data Hold from Write Time	t _{DH}	5		10		10		ns
Output 3-State from Write	t _{OTW}		50		50		60	ns

- Notes:**
1. A Write Cycle occurs during the overlap of a low CS and a low WE.
 2. OE may be both high and low in a Write Cycle.
 3. t_{AS} is specified from CS or WE, whichever occurs last.
 4. t_W is an overlap time of a low CS and a low WE.
 5. t_{WR}, t_{DS} and t_{DH} are specified from CS or WE, whichever occurs first.
 6. t_{OTW} is specified by the time when DATA OUT is floating, not defined by output level.
 7. When I/O pins are Data output mode, don't force inverse signal to those pins.

WRITE CYCLE

LOW V_{CC} DATA RETENTION CHARACTERISTICS(T_a = -40°C to +85°C, unless otherwise noted)

Parameter	Symbol	5128-12/15		5128-20		Unit	Conditions
		MIN	MAX	MIN	MAX		
V _{CC} for Data Retention	V _{CCH}	2		2		V	V _{IN} = 0V to V _{CC} , CS = V _{CC}
Data Retention Current	I _{CCH}	25°C	0.2	0.5		μA	V _{CC} = 2V CS = V _{CC} V _{IN} = 0V to V _{CC}
		60°C	1.0				
		85°C			20		
CS to Data Retention Time	t _{SU}	0		0		ns	
Operation Recovery Time	t _R		t _{RC}	t _{RC}		ns	



CAPACITANCE

(T_a = 25°C, f = 1 MHz)

Parameter	Symbol	Min.	Typ.	Max.	Unit
Input/Output Capacitance	C _{I/O}			8	pF
Input Capacitance	C _{IN}			6	pF

Note: This parameter is periodically sampled and not 100% tested.